

PATTERN INSPECTION METHOD AND INSPECTION APPARATUS

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ABSTRACT OF THE DISCLOSURE

A pattern inspection method and apparatus, wherein
the target area is limited to a line part, having a
10 simplified configuration and capable of detecting a
killer defect as a defect candidate and considerably
reducing the number of non-killer defects to be detected
as defect candidates, have been disclosed. The present
invention relates to a pattern inspection method and
15 apparatus for judging non-matching parts to be defects by
making a comparison between the same patterns having a
line part in which a line extending in the longitudinal
or transverse direction appears repetitively at a fixed
pitch, wherein an average level of gray level data is
20 calculated for each pixel columns in the direction in
which the line extends, a type of the area of each pixel
columns is classified into groups, a threshold value is
determined for each area according to the statistical
processing result of the type and the difference data of
25 each pixel column, and the difference data is judged
based on the threshold value.